L Number	Hits	Search Text	DB	Time stamp
1	1364	365/189.01.ccls.	USPAT; US-PGPUB	2002/12/27 13:30
2	312	365/189.01.ccls. and correct$	USPAT; US-PGPUB	2002/12/27 13:30
3	150	(365/189.01.ccls. and correct$) and delay	USPAT; US-PGPUB	2002/12/27 13:30
4	42	((365/189.01.ccls. and correct$) and delay) and pin	USPAT; US-PGPUB	2002/12/27 13:31
5	31	((365/189.01.ccls. and correct$) and delay) and pins	USPAT; US-PGPUB	2002/12/27 13:32
6	18	(((365/189.01.ccls. and correct$) and delay) and pins) and test$	USPAT; US-PGPUB	2002/12/27 13:32
-	2	(("5386189") or ("5367263")).PN.	USPAT; US-PGPUB	2002/12/27 13:29
-	0	((("5386189") or ("5367263")).PN.) and tdr	USPAT; US-PGPUB	2002/02/26 16:38
-	0	((("5386189") or ("5367263")).PN.) and reflectometry	USPAT; US-PGPUB	2002/02/26 16:39
-	0	((("5386189") or ("5367263")).PN.) and domain	USPAT; US-PGPUB	2002/02/26 16:39
-	0	((("5386189") or ("5367263")).PN.) and latch	USPAT; US-PGPUB	2002/02/26 16:39
-	0	((("5386189") or ("5367263")).PN.) and fifo	USPAT; US-PGPUB	2002/02/26 16:39
-	0	((("5386189") or ("5367263")).PN.) and delay	USPAT; US-PGPUB	2002/02/26 16:39
-	0	((("5386189") or ("5367263")).PN.) and clock	USPAT; US-PGPUB	2002/02/26 16:45
-	1	((("5386189") or ("5367263")).PN.) and measuring	USPAT; US-PGPUB	2002/02/26 16:45
-	5	5386189.URPN.	USPAT; US-PGPUB	2002/02/26 16:58
-	14	("4300207" | "4402055" | "4404519" | "4481627" | "4639664" | "4719411" | "4724379" | "4764926" | "4799009" | "4926363" | "5025205" | "5025210" | "5034685" | "5126953").PN.	USPAT; US-PGPUB	2002/02/26 17:00
-	6	5367263.URPN.	USPAT; US-PGPUB	2002/02/26 17:21
-	5	("4038648" | "4479088" | "4956602" | "4961053" | "5059899").PN.	USPAT; US-PGPUB	2002/02/26 17:26
-	438	clock same latch$ same signal same testing	USPAT; US-PGPUB	2002/06/23 15:02
-	154	(clock same latch$ same signal same testing) and high near speed	USPAT; US-PGPUB	2002/06/23 15:03
-	78	((clock same latch$ same signal same testing) and high near speed) and semiconductor	USPAT; US-PGPUB	2002/06/23 15:03
-	134	((clock same latch$ same signal same testing) and high near speed) and (semiconductor integrated)	USPAT; US-PGPUB	2002/06/23 15:03
-	19	(((clock same latch$ same signal same testing) and high near speed) and (semiconductor integrated)) and 324/$.ccls.	USPAT; US-PGPUB	2002/06/23 15:07
-	5	(correcting same timing same ((test$ measuring) near signal)).clm,ab,ti.	USPAT; US-PGPUB	2002/06/23 15:09
-	5	(correcting same timing same ((test$ measuring) near signal)).clm,ab,ti.	USPAT; US-PGPUB	2002/06/23 15:15
-	0	20020026613.URPN.	USPAT	2002/06/23 15:14
-	646	714/736,742.ccls.	USPAT; US-PGPUB	2002/06/23 15:29
-	3	714/736,742.ccls. and tdr	USPAT; US-PGPUB	2002/06/23 15:27
-	49	714/$.ccls. and tdr	USPAT; US-PGPUB	2002/06/23 15:29
-	1	6192496.URPN.	USPAT	2002/06/23 15:44

–	13	("3832575" | "4994732" | "5003260" | "5083083" | "5212443" | "5225772" | "5390194" | "5471145" | "5485096" | "5504432" | "5590136" | "5633596" | "6025708").PN.	USPAT	2002/06/23 15:44
–	26	4994732.URPN.	USPAT	2002/06/23 15:52
–	4	("4439858" | "4500993" | "4598245" | "4646299").PN.	USPAT	2002/06/23 16:15
–	13	("3832575" | "4994732" | "5003260" | "5083083" | "5212443" | "5225772" | "5390194" | "5471145" | "5485096" | "5504432" | "5590136" | "5633596" | "6025708").PN.	USPAT	2002/06/23 16:17
–	54	integrated same latch$ same fifo	USPAT; US-PGPUB	2002/06/23 16:20
–	10	5388074.URPN.	USPAT	2002/06/23 16:30
–	2	"09127205"	EPO; JPO; DERWENT; IBM_TDB	2002/06/24 12:08
–	0	9127205.URPN.	USPAT	2002/06/24 12:06
–	0	9127205.URPN.	USPAT	2002/06/24 12:06
–	1	1997-323851.NRAN.	DERWENT	2002/06/24 12:06
–	0	9127205.URPN.	USPAT	2002/06/24 12:06
–	1	1997-323851.NRAN.	DERWENT	2002/06/24 12:06
–	2	"11053900"	EPO; JPO; DERWENT; IBM_TDB	2002/06/24 12:09
–	0	11053900.URPN.	USPAT	2002/06/24 12:08
–	1	("6061282").PN.	USPAT; US-PGPUB	2002/06/24 12:09
–	1	6061282.URPN.	USPAT	2002/06/24 12:09
–	3	("5757705" | "5805514" | "5825712").PN.	USPAT	2002/06/24 12:10
–	311	(324/763).CCLS.	USPAT; US-PGPUB	2002/06/25 11:15
–	55	((324/763).CCLS.) and clock$ and latch$	USPAT; US-PGPUB	2002/06/25 11:16
–	38	((324/763).CCLS.) and clock and latch	USPAT; US-PGPUB	2002/06/25 11:53
–	0	6119253.URPN.	USPAT	2002/06/25 11:22
–	4	("5198758" | "5406567" | "5528162" | "5732209").PN.	USPAT	2002/06/25 11:22
–	4	5847561.URPN.	USPAT	2002/06/25 11:44
–	17	(((324/763).CCLS.) and clock$ and latch$) not (((324/763).CCLS.) and clock and latch)	USPAT; US-PGPUB	2002/06/25 12:14
–	33	(((324/763).CCLS.) and clock and latch) and tim$	USPAT; US-PGPUB	2002/06/25 12:16
–	17	((((324/763).CCLS.) and clock$ and latch$) not (((324/763).CCLS.) and clock and latch)) and tim$	USPAT; US-PGPUB	2002/06/25 12:16
–	0	(((((324/763).CCLS.) and clock$ and latch$) not (((324/763).CCLS.) and clock and latch)) and tim$) and calibration	USPAT; US-PGPUB	2002/06/25 12:16
–	5	(((((324/763).CCLS.) and clock and latch) and tim$) and calibration	USPAT; US-PGPUB	2002/06/25 12:23
–	14	((324/763).CCLS.) and trigger and latch$ and clock	USPAT; US-PGPUB	2002/06/25 12:24
–	4	((324/763).CCLS.) and electrical near length	USPAT; US-PGPUB	2002/06/25 12:26
–	294	324/$.ccls. and electrical near length	USPAT; US-PGPUB	2002/06/25 12:26
–	16	324/$.ccls. and ((electrical near length) with pin)	USPAT; US-PGPUB	2002/06/25 12:29
–	3	714/$.ccls. and ((electrical near length) with pin)	USPAT; US-PGPUB	2002/06/25 12:31
–	9	((electrical near length) with pin) and calibration	USPAT; US-PGPUB	2002/06/25 12:33
–	170	correct$ near3 correct$ near waveform	USPAT; US-PGPUB	2002/06/25 12:35
–	96	(correct$ near3 correct$ near waveform) and timing	USPAT; US-PGPUB	2002/06/25 12:35

–	13	correct$ near3 correct$ near waveform same timing	USPAT; US-PGPUB	2002/06/25 12:36
–	283	324/130.ccls.	USPAT; US-PGPUB	2002/06/25 13:08
–	2	"07309821"	EPO; JPO; DERWENT	2002/06/28 16:15
–	0	07309821.ap,pran.	EPO; JPO; DERWENT	2002/06/28 16:16
–	2	07309821.did.	EPO; JPO; DERWENT	2002/06/28 16:16
–	2	09127205.pn,did.	EPO; JPO; DERWENT	2002/06/28 16:18
–	1	1997-323851.NRAN.	DERWENT	2002/06/28 16:17
–	2	11053900.pn,did.	EPO; JPO; DERWENT	2002/06/28 16:19
–	1	1999-134864.NRAN.	DERWENT	2002/06/28 16:19
–	3	(("5388074") or ("4994732") or ("5563524")).PN.	USPAT; US-PGPUB	2002/06/29 13:29
–	2	(("5386189") or ("5367263")).PN.	USPAT; US-PGPUB	2002/06/29 13:45
–	5	5386189.URPN.	USPAT	2002/06/29 13:46
–	14	("4300207" | "4402055" | "4404519" | "4481627" | "4639664" | "4719411" | "4724379" | "4764926" | "4799009" | "4926363" | "5025205" | "5025210" | "5034685" | "5126953").PN.	USPAT	2002/06/29 13:49
–	6	5367263.URPN.	USPAT	2002/06/29 13:54
–	5	("4038648" | "4479088" | "4956602" | "4961053" | "5059899").PN.	USPAT	2002/06/29 13:55
–	5	("4038648" | "4479088" | "4956602" | "4961053" | "5059899").PN.	USPAT	2002/06/29 13:58
–	14	4639664.URPN.	USPAT	2002/06/29 13:59
–	3	(("5563524") or ("5790411") or ("6061282")).PN.	USPAT; US-PGPUB	2002/07/13 18:26
–	2	((("5563524") or ("5790411") or ("6061282")).PN.) and timing	USPAT; US-PGPUB	2002/07/13 18:31

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Author (Inventor): TAMAKI SATOSHI (JP)
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    EP 898284   A2   19990224   EP 98114466   A   19980731 (BASIC)
    EP 898284   A3   19990915   EP 98114466   A   19980731
    JP 11053900   A2   19990226   JP 97220973   A   19970731
    JP 3262033   B2   20020304   JP 97220973   A   19970731
    US 6061282   A   20000509   US 126926   A   19980731
    TW 392169   B   20000601   TW 87112544   A   19980730
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